

THE U.S. PATENT AND TRADEMARK OFFICE October 21, 2009

Applicants : Masashi KUMAGAI et al

For COPPER ELECTROLYTIC SOLUTION AND ELECTROLYTIC

COPPER FOIL PRODUCED THEREWITH

Serial No. : 10/531 645 Group:

Confirmation No.: 1483

Filed : April 15, 2005 Examiner: Mendez

International Application No.: PCT/JP2003/013044 International Filing Date : October 10, 2003

Atty. Docket No.: 4700.P0312US

Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

NOTICE OF APPEAL FROM THE PRIMARY EXAMINER TO THE BOARD OF APPEALS

Sir:

Applicant hereby appeals to the Board of Appeals from the decision mailed July 23, 2009 of the Primary Examiner finally rejecting Claims 4-8.

(Please see following page.)

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on October 21, 2009.

Respectfully submitted,

10/26/2009 RMEBRAHT 00000018 10531645

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540.00 OP

The item(s) checked below are appropriate:

- [] A Petition and fee for extension accompany this Notice.
- [X] Appeal fee:
 - [X] \$540.00 (large entity).
 - [] \$270.00 (small entity). Small entity status is claimed, see 37 CFR 1.27.
- [X] A check for \$540.00 is enclosed to cover fees.
- [] Please charge the Appeal Fee of \$_____ to Deposit Account 06-1382.
- [X] The Commissioner is hereby authorized to charge any additional fees required by this paper or to credit any overpayment to Deposit Account No. 06-1382.
- [X] An acknowledgement Postal Card is enclosed.

Respectfully submitted,

Terryence F Chapman

TFC/smd

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Encl: Listed Above

150.10/08